Search Notes							

Application/Control No.	Applicant(s)/Patent under Reexamination
10/619,046	HAN ET AL.
Examiner	Art Unit
Khai M. Nauven	2617

	SEARCHED		
Class	Subclass	Date	Examiner
see	previous		KN
		. "	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
•				
	<u> </u>			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East (see attached)	10/30/2007	KN
·		
· · · · · · · · · · · · · · · · · · ·		